Amend1ments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

1. (Previously Presented) An integral polishing pad which performs a polishing operation by moving in contact with a surface of an object being polished, the integral polishing pad comprising:

an elastic support layer, which is made of a nonporous solid uniform polymer and at least partially transparent to a light source used to detect the surface state of the object being polished; and

a polishing layer, which is formed on the elastic support layer and semitransparent to the light source, and has a higher hardness than the elastic support layer,

wherein the elastic support layer and the polishing layer are made of materials chemically compatible with each other so that a structural border between the elastic support layer and the polishing layer does not exist, and

the polishing layer comprises a polymeric matrix made from a material chemically compatible with the elastic support layer and a plurality of liquid microelements embedded in the polymeric matrix, and

a plurality of open pores defined by the embedded liquid microelements are distributed across a surface of the polishing layer.

- 2. (Original) The integral polishing pad of claim 1, wherein the elastic support layer has a hardness of 40 to 80 shore A.
- 3. (Original) The integral polishing pad of claim 1, wherein the polishing layer has a hardness of 40 to 80 shore D.
- 4. (Original) The integral polishing pad of claim 1, wherein each of the elastic support layer and the polishing layer comprises at least one material selected from the group consisting of polyurethane, polyether, polyester, polysulfone, polyacryl, polycarbonate, polyethylene,

polymethylmetacrylate, polyvinyl acetate, polyvinyl chloride, polyethyleneimine, polyethersulfone, polyetherimide, polyketone, melamine, nylon, and hydrocarbon fluoride.

5-6. (Canceled)

- 7. (Previously Presented) The integral polishing pad of claim 1, wherein when the surface of the polishing layer is abraded during the polishing operation, the embedded liquid microelements are exposed at the surface of the polishing layer so that the open pores are continuously formed.
- 8. (Previously Presented) The integral polishing pad of claim 1, wherein a material for the embedded liquid microelements is a liquid material which is chemically incompatible with the polymeric matrix.
- 9. (Original) The integral polishing pad of claim 8, wherein the liquid material comprises at least one material selected from the group consisting of aliphatic mineral oil, aromatic mineral oil, silicon oil without a hydroxyl group in a molecule, soybean oil, coconut oil, palm oil, cotton seed oil, camellia oil, and hardened oil.
- 10. (Original) The integral polishing pad of claim 9, wherein the content of the liquid material is 20-50 weight percent, based on the total weight of a material for the polymeric matrix.
- 11. (Currently Amended) The integral polishing pad of claims 1, wherein the polishing layer comprises a polymeric matrix made from a material chemically compatible with the elastic support layer and a plurality of embedded liquid microelements and hollow polymeric microelements, which are included within the polymeric matrix, and
- a plurality of open pores, which are defined by the embedded liquid microelements and the hollow polymeric microelements, are distributed across a surface of the polishing layer.

- 12. (Original) The integral polishing pad of claim 1, further comprising a structure or pattern including a flow channel in a surface of the polishing layer in order to facilitate delivery of a polishing slurry.
- 13. (Previously Presented) The integral polishing pad of claim 1, wherein the polishing layer comprises a transparent region, which overlaps the transparent portion of the elastic support layer and is transparent to the light source, and a remaining region, except for the transparent region, which has a higher hardness than the elastic support layer, and the elastic support layer, the transparent region, and the remaining region are made from materials chemically compatible with one another so that structural borders among them do not exist.
- 14. (Original) The integral polishing pad of claim 13, wherein the elastic support layer has a hardness of 40 to 80 shore A.
- 15. (Original) The integral polishing pad of claim 13, wherein the remaining region of the polishing layer except for the transparent region has a hardness of 40 to 80 shore D.
- 16. (Original) The integral polishing pad of claim 13, wherein each of the elastic support layer and the remaining region of the polishing layer comprises at least one material selected from the group consisting of polyurethane, polyether, polyester, polysulfone, polyacryl, polycarbonate, polyethylene, polymethylmetacrylate, polyvinyl acetate, polyvinyl chloride, polyethyleneimine, polyethersulfone, polyetherimide, polyketone, melamine, nylon, and hydrocarbon fluoride.
- 17. (Original) The integral polishing pad of claim 13, wherein the transparent region is made of an organic polymer or an inorganic material coated with the organic polymer.

- 18. (Original) The integral polishing pad of claim 17, wherein the organic polymer comprises at least one material selected from the group consisting of a polyurethane, polyester, nylon, acryl resin, epoxy resin, polyethylene, polystyrene, polyvinyl chloride, polytetrafluoroethylene, polyvinylidene fluoride, and polyether sulfone.
- 19. (Original) The integral polishing pad of claim 18, wherein the elastic support layer is made of a nonporous solid uniform polymeric elastic material,
- 20. (Currently Amended) The integral polishing pad of any one of claims 13, wherein the remaining region of the polishing layer except for the transparent region comprises a polymeric matrix made from a material chemically compatible with the elastic support layer and a plurality of embedded liquid microelements and/or hollow polymeric microelements, which are included within the polymeric matrix, and

a plurality of open pores, which are defined by the embedded liquid microelements and/or the hollow polymeric microelements, are distributed across a surface of the polishing layer.

- 21. (Original) The integral polishing pad of claim 20, wherein when the surface of the polishing layer is abraded during the polishing operation, the embedded liquid microelements and/or the hollow polymeric microelements are exposed at the surface of the polishing layer so that the open pores are continuously formed.
- 22. (Original) The integral polishing pad of claim 20, wherein a material for the embedded liquid microelements is a liquid material which is chemically incompatible with the polymeric matrix.
- 23. (Original) The integral polishing pad of claim 22, wherein the liquid material comprises at least one material selected from the group consisting of aliphatic mineral oil, aromatic mineral oil, silicon oil without a hydroxyl group in a molecule, soybean oil, coconut oil, palm oil, cotton seed oil, camellia oil, and hardened oil.

Appl. No. 10/648,403 Response dated: October 14, 2005 Reply to Office action of June 15, 2005

24. (Original) The integral polishing pad of claim 22, wherein the content of the liquid material is 20-50 weight percent, based on the total weight of a material for the polymeric matrix.

25. (Original) The integral polishing pad of claim 13, further comprising a texture or pattern including a flow channel in a surface of the polishing layer in order to facilitate delivery of a polishing slurry.

26-30. (Canceled)

31. (Currently Amended) The integral polishing pad of any one of claims 2, wherein the polishing layer comprises a polymeric matrix made from a material chemically compatible with the elastic support layer and a plurality of embedded liquid microelements and hollow polymeric microelements, which are included within the polymeric matrix, and

a plurality of open pores, which are defined by the embedded liquid microelements and the hollow polymeric microelements, are distributed across a surface of the polishing layer.

32. (Currently Amended) The integral polishing pad of any one of claims 3, wherein the polishing layer comprises a polymeric matrix made from a material chemically compatible with the elastic support layer and a plurality of embedded liquid microelements and hollow polymeric microelements, which are included within the polymeric matrix, and

a plurality of open pores, which are defined by the embedded liquid microelements and the hollow polymeric microelements, are distributed across a surface of the polishing layer.

33. (Currently Amended) The integral polishing pad of any one of claims 4, wherein the polishing layer comprises a polymeric matrix made from a material chemically compatible with the elastic support layer and a plurality of embedded liquid microelements and hollow polymeric microelements, which are included within the polymeric matrix, and

a plurality of open pores, which are defined by the embedded liquid microelements and the hollow polymeric microelements, are distributed across a surface of the polishing layer. 34. (Currently Amended) The integral polishing pad of any one of claims 14, wherein the remaining region of the polishing layer except for the transparent region comprises a polymeric matrix made from a material chemically compatible with the elastic support layer and a plurality

of embedded liquid microelements and/or hollow polymeric microelements, which are included

within the polymeric matrix, and

a plurality of open pores, which are defined by the embedded liquid microelements

and/or the hollow polymeric microelements, are distributed across a surface of the polishing

layer.

35. (Previously Presented) The integral polishing pad of claim 14, wherein when the

surface of the polishing layer is abraded during the polishing operation, the embedded liquid

microelements and/or the hollow polymeric microelements are exposed at the surface of the

polishing layer so that the open pores are continuously formed.

36. (Previously Presented) The integral polishing pad of claim 14, wherein a material for

the embedded liquid microelements is a liquid material which is chemically incompatible with

the polymeric matrix.

37. (Previously Presented) The integral polishing pad of claim 14, wherein the liquid

material comprises at least one material selected from the group consisting of aliphatic mineral

oil, aromatic mineral oil, silicon oil without a hydroxyl group in a molecule, soybean oil, coconut

oil, palm oil, cotton seed oil, camellia oil, and hardened oil.

38. (Previously Presented) The integral polishing pad of claim 14, wherein the content of

the liquid material is 20-50 weight percent, based on the total weight of a material for the

polymeric matrix.

Page 8 of 13

39. (Currently Amended) The integral polishing pad of any one of claims 15, wherein the remaining region of the polishing layer except for the transparent region comprises a polymeric matrix made from a material chemically compatible with the elastic support layer and a plurality

of embedded liquid microelements and/or hollow polymeric microelements, which are included

within the polymeric matrix, and

a plurality of open pores, which are defined by the embedded liquid microelements

and/or the hollow polymeric microelements, are distributed across a surface of the polishing

layer.

40. (Previously Presented) The integral polishing pad of claim 15, wherein when the

surface of the polishing layer is abraded during the polishing operation, the embedded liquid

microelements and/or the hollow polymeric microelements are exposed at the surface of the

polishing layer so that the open pores are continuously formed.

41. (Previously Presented) The integral polishing pad of claim 15, wherein a material for

the embedded liquid microelements is a liquid material which is chemically incompatible with

the polymeric matrix.

42. (Previously Presented) The integral polishing pad of claim 15, wherein the liquid

material comprises at least one material selected from the group consisting of aliphatic mineral

oil, aromatic mineral oil, silicon oil without a hydroxyl group in a molecule, soybean oil, coconut

oil, palm oil, cotton seed oil, camellia oil, and hardened oil.

43. (Previously Presented) The integral polishing pad of claim 15, wherein the content of

the liquid material is 20-50 weight percent, based on the total weight of a material for the

polymeric matrix.

Page 9 of 13

44. (Currently Amended) The integral polishing pad of any one of claims 16, wherein the

remaining region of the polishing layer except for the transparent region comprises a polymeric

matrix made from a material chemically compatible with the elastic support layer and a plurality

of embedded liquid microelements and/or hollow polymeric microelements, which are included

within the polymeric matrix, and

a plurality of open pores, which are defined by the embedded liquid microelements

and/or the hollow polymeric microelements, are distributed across a surface of the polishing

layer.

45. (Previously Presented) The integral polishing pad of claim 16, wherein when the

surface of the polishing layer is abraded during the polishing operation, the embedded liquid

microelements and/or the hollow polymeric microelements are exposed at the surface of the

polishing layer so that the open pores are continuously formed.

46. (Previously Presented) The integral polishing pad of claim 16, wherein a material for

the embedded liquid microelements is a liquid material which is chemically incompatible with

the polymeric matrix.

47. (Previously Presented) The integral polishing pad of claim 16, wherein the liquid

material comprises at least one material selected from the group consisting of aliphatic mineral

oil, aromatic mineral oil, silicon oil without a hydroxyl group in a molecule, soybean oil, coconut

oil, palm oil, cotton seed oil, camellia oil, and hardened oil.

48. (Previously Presented) The integral polishing pad of claim 16, wherein the content of

the liquid material is 20-50 weight percent, based on the total weight of a material for the

polymeric matrix.

Page 10 of 13

SHN-0040 / PO-2003-0009/US